

Journal of Materials Chemistry C

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Cite this: DOI: 10.1039/c0xx00000x

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ARTICLE TYPE

Hollow cathode plasma-assisted atomic layer deposition of crystalline AlN, GaN and Al_xGa_{1-x}N thin films at low temperatures

Cagla Ozgit-Akgun,^{*a,b} Eda Goldenberg,^a Ali Kemal Okyay^{a,b,c} and Necmi Biyikli^{*a,b}

Received (in XXX, XXX) Xth XXXXXXXXX 20XX, Accepted Xth XXXXXXXXX 20XX

DOI: 10.1039/b000000x

Authors report on the use of hollow cathode plasma for low-temperature plasma-assisted atomic layer deposition (PA-ALD) of crystalline AlN, GaN and Al_xGa_{1-x}N thin films with low impurity concentrations. Depositions were carried out at 200 °C using trimethylmetal precursors and NH₃ or N₂/H₂ plasma. X-ray photoelectron spectroscopy showed the presence of 2.5-3 at.% O in AlN, and 1.5-1.7 at.% O in GaN films deposited using NH₃ and N₂/H₂ plasma, respectively. No C impurities were detected within the films. Secondary ion mass spectroscopy analyses performed on the films deposited using NH₃ plasma revealed the presence of O, C (both < 1 at.%), and H impurities. GIXRD patterns indicated polycrystalline thin films with wurtzite crystal structure. Hollow cathode PA-ALD parameters were optimized for AlN and GaN thin films using N₂/H₂ plasma. Trimethylmetal and N₂/H₂ saturation curves evidenced the self-limiting growth of AlN and GaN at 200 °C. AlN exhibited linear growth with a growth per cycle (GPC) of ~1.0 Å. For GaN, GPC decreased with the increasing number of deposition cycles, indicating substrate-enhanced growth. GPC calculated from a 900-cycle GaN deposition was 0.22 Å. Ellipsometric spectra of the samples were modeled using the Cauchy dispersion function, from which the refractive indices of 59.2-nm-thick AlN and 20.1-nm-thick GaN thin films were determined as 1.94 and 2.17 at 632 nm, respectively. Spectral transmission measurements of AlN, GaN and Al_xGa_{1-x}N thin films grown on double side polished sapphire substrates revealed near-ideal visible transparency with minimal absorption. Optical band edge values of the Al_xGa_{1-x}N films shifted to lower wavelengths with the increasing Al content, indicating the tunability of band edge values with alloy composition.

Introduction

In the last few decades, considerable research has been devoted to the growth and characterization of III-nitride compound semiconductors (AlN, GaN, InN) and their alloys, which emerged as versatile and high-performance materials for a wide range of electronic and optoelectronic device applications. Wurtzite type III-nitrides exhibit direct band gaps, which extend from ultraviolet (UV) to the mid-IR spectrum with values of 6.2, 3.4 and 0.64 eV for AlN, GaN, and InN, respectively.^{1,2} This feature allows the band gap of any ternary or quaternary III-nitride alloy to be easily tuned within the specified limits to adjust a particular application. Metalorganic chemical vapor deposition (MOCVD)^{3,4} and molecular beam epitaxy (MBE)⁵ have already been proven to be successful techniques for achieving high-quality epitaxial III-nitride layers with low impurity concentrations and decent electrical properties. However, both of these methods employ high growth temperatures, which is neither compatible with the existing CMOS technology nor suitable for temperature-sensitive device layers (e.g. In-rich In_xGa_{1-x}N) and substrates (e.g. glass, flexible polymers, etc.). This incompatibility necessitates the development of alternative low-temperature processes for the deposition of III-nitride thin films

and their alloys.

Atomic layer deposition (ALD) is a low-temperature material growth method, which is based on self-terminating surface reactions.⁶ Unlike chemical vapor deposition (CVD), in ALD, precursors are pulsed into the reactor one at a time, separated by purging and/or evacuation periods. Unless decomposition occurs, precursor molecules do not tend to react with themselves and hence reaction terminates when all the available reactive surface sites are occupied. This special growth mechanism is termed as “self-limiting” and results in highly uniform and conformal thin films, whose thicknesses can be controlled at the sub-angstrom scale. This makes ALD a powerful method especially for depositing films on nanostructured templates,⁷⁻⁹ which is considered as a successful approach for improving efficiency and/or sensitivity of devices through surface area enhancement. Moreover, alloy thin films can be easily deposited using ALD, either by controlling the relative vapor pressures of the precursors which are being pulsed into the reactor simultaneously during one of the half-cycles, or by designing a cycle that consists of sub-cycles of the constituent materials. The latter, which is generally named as “digital alloying”, is a unique and facile route for obtaining alloy thin films with well-defined compositions.

Thermal ALD of AlN has been extensively studied using ammonia (NH₃) and various Al precursors: aluminum trichloride

(AlCl₃),¹⁰ dimethylethylamine alane (Me₂EtN:AlH₃),¹¹ triethylaluminum (AlEt₃),¹² trimethylaluminum (AlMe₃),¹³ trimethylamine alane (Me₃N:AlH₃)¹⁴ (with deuterated ammonia (ND₃)), and tris(dimethylamido)aluminum (Al₂(NMe₂)₆).¹⁵ Plasma- and UV-assisted ALD of AlN have also been reported for AlCl₃-NH₃/H₂,^{16,17} AlMe₃-NH₃,^{18,19} and AlMe₃-N₂/H₂²⁰ combinations. Although AlCl₃ is a highly reactive and thermally stable precursor, which yielded good results in terms of achieving true ALD conditions, the use of halogenated precursors is in general not preferred due to several reasons. Most importantly, their reaction with hydrogen-containing nonmetals results in gaseous corrosive by-products (HCl in the case of chloride precursors), which can etch the deposited film, as well as the reactor components. Furthermore, halide ligands incorporate into the growing film and remain as impurities. They also create a memory effect in the chamber; i.e. residual halides in the system contaminate the subsequently deposited films for a long period of time following the use of a halogenated precursor. Among all the metalorganic Al precursors listed above, AlMe₃ is probably the most recognized one due to the well-known AlMe₃-H₂O thermal ALD process that is designed for depositing dielectric Al₂O₃ layers.⁶ Unfortunately, thermal ALD of AlN using AlMe₃ and NH₃ is not possible since these two precursors only react at temperatures where AlMe₃ self-decomposition occurs.¹³ Therefore, true ALD conditions for the deposition of AlN using AlMe₃ and NH₃ can only be achieved if the deposition temperature is lowered by enhancing the reactivity of NH₃ using an external energy source, such as plasma. Plasma-assisted ALD (PA-ALD) of nitride thin films is not limited with the use of NH₃; alternatively, a mixture of N₂ and H₂ gases can also be employed to create similar plasma radicals. Recently, our group reported on the PA-ALD of polycrystalline wurtzite AlN thin films at temperatures ranging from 100-500 °C.²¹⁻²³ Films deposited at temperatures within the ALD window (100-200 °C for both NH₃ and N₂/H₂ processes) were C-free and had low O concentrations (< 3 at.%) despite 5N-grade plasma gases were used without any further purification. It is worth noting that the number of publications focusing on the PA-ALD (or plasma-assisted atomic layer epitaxy, PA-ALE) of AlN using AlMe₃ has increased considerably in the last few years.²⁴⁻²⁸ AlN films deposited using PA-ALD were reported to be either amorphous or polycrystalline.²⁴⁻²⁷ In a very recent study, Nepal et al.²⁸ demonstrated the PA-ALE of AlN films at 200-650 °C using AlMe₃ and N₂ plasma, and emphasized the significance of *ex situ* and *in situ* surface pretreatments for obtaining epitaxial thin films. PA-ALD and -ALE grown AlN thin films were used in resistive memories,²⁹ transistors,³⁰⁻³³ and in other devices for work function tuning³⁴ and passivation.³⁵⁻³⁷

When compared to AlN, significantly less number of publications concentrated on the ALD of GaN thin films. Thermal and plasma-assisted ALE, as well as thermal ALD of GaN have been studied at temperatures > 450 °C using triethylgallium (GaEt₃),³⁸ trimethylgallium (GaMe₃),^{39,40} and gallium trichloride (GaCl₃)^{41,42} precursors. Lower ALE growth temperatures (350-400 °C) were achieved when gallium chloride (GaCl) was used as the Ga precursor.⁴³ Sumakeris et al.⁴⁴ used a novel reactor design that employs hot filaments to decompose the NH₃ and deposited epitaxial GaN films using GaEt₃ within the

temperature range of 150-650 °C. Recently, Sharp et al.⁴⁵ presented their results on the PA-ALD of GaN thin films using GaEt₃ and N₂/H₂ plasma. In their study, the concentrations of O and C impurities in GaN films were reported as ≥ 3 at.%. Our initial efforts for depositing GaN thin films using GaEt₃ or GaMe₃ with NH₃ plasma resulted in amorphous thin films with high O concentrations (~20 at.%).^{46,47} Although – at first – the most probable source of this contamination was presumed as the O-containing impurities in the 5N-grade NH₃ gas, subsequent experiments revealed the true source as the quartz tube of inductively coupled plasma source itself. Such plasma-related oxygen contamination was also reported for GaN thin films grown by remote plasma enhanced CVD.⁴⁸ In view of these circumstances, the choice of N-containing plasma gas (N₂, N₂/H₂ or NH₃) determined the severity of O incorporation into AlN and GaN films deposited by PA-ALD.⁴⁹ We were able to deposit polycrystalline wurtzite GaN thin films with 4.7 at.% O and 4.2 at.% C impurities using the GaMe₃-N₂/H₂ PA-ALD process at 200 °C. As an effort to completely avoid this contamination problem, we replaced the original quartz-based inductively coupled RF-plasma (ICP) source of the ALD system with a stainless steel hollow cathode plasma (HCP) source,⁵⁰ which recently has been used for the deposition of epitaxial GaN thin films by migration enhanced afterglow.⁵¹

Here, we report on the low-temperature hollow cathode PA-ALD (HCPA-ALD) of crystalline AlN, GaN and Al_xGa_{1-x}N thin films with low impurity concentrations. To the best of our knowledge, this is the first study reporting on the integration of HCP and ALD, as well as the first low-temperature self-limiting growth of crystalline Al_xGa_{1-x}N thin films. Materials characterization efforts including structural, chemical, surface, and optical analyses are presented in detail.

Experimental details

Hollow cathode plasma-assisted atomic layer deposition

AlN, GaN and Al_xGa_{1-x}N thin films were deposited at 200 °C in a modified Fiji F200-LL ALD reactor (Ultratech/Cambridge NanoTech Inc.), which is backed by an Edwards nXDS20iC dry scroll vacuum pump. In this modified configuration, the original quartz-based ICP source of the ALD system was replaced with a stainless steel HCP source (Meaglow Ltd.). The original RF power supply (Seren IPS Inc., R301), matching network controller (Seren IPS Inc., MC2) and automatic matching network (Seren IPS Inc., AT-3) units were used to activate the HCP discharge. Prior to depositions, Si (100), Si (111), and *c*-plane sapphire substrates were cleaned by sequential ultrasonic agitation in 2-propanol, acetone, methanol, and deionized (DI) water. For the native oxide removal, Si substrates were further dipped into dilute hydrofluoric acid solution (HF, 2 vol.%) for ~2 min, then rinsed with DI water and dried with N₂. Substrates were then immediately loaded to the reactor using a load lock and kept at the deposition temperature for at least 20 min before the process was initiated. All depositions were started with the metalorganic pulse. Trimethylaluminum (AlMe₃) and trimethylgallium (GaMe₃) were used as the Al and Ga precursors, respectively. AlMe₃ was kept at room temperature, whereas GaMe₃ was cooled down to 6 °C using a home-made Peltier

cooling system. 5N-grade NH₃, N₂ and H₂ plasma gases, and the carrier gas, Ar, were further purified using MicroTorr gas purifiers. Metalorganic precursor pulses and plasma gases were carried from separate lines by 30 and 100 sccm Ar, respectively. Speed of the Adixen ATH 400M turbo pump was adjusted in order to obtain a base pressure of ~150 mTorr. Remote plasma (300 W) was activated at each cycle only during the flow of N-containing plasma gas. Unless stated otherwise, system was purged for 10 s after each exposure.

10 Film characterization

Ellipsometric spectra were recorded in the wavelength range of 300-1000 nm for AlN, and 400-1200 nm for GaN and Al_xGa_{1-x}N thin films at three angles of incidence (65°, 70°, and 75°) using a variable angle spectroscopic ellipsometer (V-VASE, J.A. Woollam Co. Inc.) with a rotating analyzer. Optical constants and film thicknesses were extracted using the Cauchy dispersion function using a two-layer model; i.e. Cauchy/Si (0.5 nm). Chemical compositions and bonding states were determined by X-ray photoelectron spectroscopy (XPS) using Thermo Scientific K-Alpha spectrometer with a monochromatized Al K_α X-ray source. Pass energy, step size, and spot size were 30 eV, 0.1 eV, and 400 μm, respectively. Etching of the samples was carried out *in situ* with a beam of Ar ions having an acceleration voltage of 1 kV. High-resolution XPS (HR-XPS) data were corrected for charging by shifting peaks with respect to the adventitious C peak located at 284.8 eV. Peak deconvolution was performed using the Avantage Software, without applying any restrictions to spectral location and full width at half maximum (FWHM) values. Secondary ion mass spectroscopy (SIMS) measurements were realized by the Evans Analytical Group (EAG) using a Physical Electronics Quadrupole SIMS instrument. Analyses were carried out using EAG's proprietary analytical protocols. Calibrations were based on relevant AlN, GaN and AlGa_xN internal standards for concentration and depth. Atomic mixing or depth resolution of the primary ion beam setup was < 9 nm/decade. X-ray reflectivity (XRR) and grazing-incidence X-ray diffraction (GIXRD) measurements were carried out in a PANalytical X'Pert PRO MRD diffractometer using Cu K_α radiation. GIXRD patterns were obtained by performing 10 repeated scans within the 2Theta range of 20-80° with a step size of 0.1° and counting time of 10 s. These scans were then added together in order to obtain a single GIXRD pattern with good intensity values. Peak positions and the corresponding interplanar spacing values were obtained by fitting the GIXRD data using PANalytical X'Pert HighScore Plus Software. Using the same software, line profile analysis (LPA) was applied to each GIXRD pattern. Instrumental broadening was corrected using a polycrystalline silicon monitor sample, whose GIXRD data was obtained by performing 3 repeated scans within the 2Theta range of 10-145° with a step size and counting time of 0.06° and 10 s, respectively. XRR data were fitted by the PANalytical X'Pert Reflectivity Software using a four-layer model, i.e. Al₂O₃ (or Ga₂O₃)/AlN (or GaN)/SiO₂/Si. FEI Tecnai G2 F30 transmission electron microscope (TEM) at an operating voltage of 300 kV was used for the imaging of samples prepared by FEI Nova 600i Nanolab focused ion beam (FIB) system. Samples were prepared at an acceleration voltage of 30 kV, using various beam currents ranging from 50 pA to 21 nA. For the GaN and Al_xGa_{1-x}N thin film samples, damage layers

formed at the film/substrate interfaces were treated by FIB milling using beam voltages of 5 and 2 kV, respectively. An atomic force microscope (AFM, Park Systems Corp., XE-100) operating in the contact mode was used to reveal surface morphologies of the deposited thin films. Normal incidence transmission measurements were performed relative to air within the range of 220-900 nm using an Ocean Optics UV-VIS-NIR single beam spectrophotometer (HR4000CG-UV-NIR).

Results and discussion

AlN and GaN thin films deposited using non-optimized HCPA-ALD parameters

AlN and GaN thin films were first deposited on 4" Si (100) substrates at 200 °C using non-optimized process parameters. 800 cycles were deposited, where one cycle consisted of: 0.1 s AlMe₃ or 0.015 s GaMe₃/10 s Ar purge/40 s, 300 W NH₃ plasma (50 sccm) or N₂/H₂ plasma (50 sccm each)/10 s Ar purge. Table 1 summarizes the spectroscopic ellipsometry (SE) results obtained from AlN and GaN thin film samples deposited using NH₃ and N₂/H₂ plasma processes, where average thickness (t_{avg}), average refractive index (n_{avg}), and uniformity data were obtained by the evaluation of spectra taken from five different points on the Si 4" wafer (the center and the edges). Growth per cycle (GPC) was calculated by dividing t_{avg} to number of cycles applied, assuming that a constant amount of material was deposited in each cycle. When compared to N₂/H₂ plasma, the use of NH₃ plasma resulted in slightly higher GPC values for both AlN and GaN thin films. On the other hand, films deposited using N₂/H₂ plasma were better in terms of thickness uniformity. Although these deposition experiments were carried out using HCPA-ALD parameters that are not optimized for true ALD conditions, resulting films were reasonably uniform with wafer-level uniformity of $\leq \pm 1.5\%$. It is also worth mentioning that we achieved higher GPC values for AlN (1.02 and 0.96 Å for NH₃ and N₂/H₂ plasma processes, respectively) using the present configuration; GPC values that we obtained using the previous configuration with quartz-based ICP source (described elsewhere²¹) were 0.86²¹ and 0.55 Å²³ for NH₃ and N₂/H₂ plasma processes, respectively. Although this improvement may be related to the higher plasma density of the HCP source, this cannot be stated for sure since the base pressure and Ar carrier flow rates were not same for the current and previous configurations. Refractive indices of the AlN thin films deposited using NH₃ and N₂/H₂ plasma were 1.98 and 1.99 at 632 nm, respectively, which are higher than the values measured for AlN thin films deposited using quartz-based ICP source and in good agreement with the values given in literature for polycrystalline AlN thin films.⁵² We measured the refractive indices of GaN films deposited using NH₃ and N₂/H₂ plasma as 2.17 and 2.14, respectively, which are comparable to values given in literature.⁵³

XPS survey scans detected 6-11 at.% C and 15-30 at.% O on the AlN and GaN film surfaces. AlN surfaces were more prone to atmospheric oxidation (25-30 at.% O) as compared to GaN surfaces (15-16 at.% O). Additional XPS survey scans were obtained with constant time intervals (e.g. 60 s) as the samples in the ultra high vacuum (UHV) chamber of XPS system were etched with a beam of Ar ions. For all the four samples, C 1s peak disappeared with the first etch; therefore no C was detected

in the subsequent scans. O concentrations in the AlN thin films gradually decreased with each etch, and became constant for $t_{etch} \geq 300$ s. XPS survey scan obtained after 600 s of etch revealed the elemental composition of AlN thin film deposited using NH_3 plasma as 50.45 at.% Al, 45.56 at.% N, 2.45 at.% O. The remaining 1.54 at.% corresponds to Ar, which incorporates into samples during ion etching. Elemental composition of the AlN deposited using N_2/H_2 plasma was very similar to that deposited using NH_3 plasma. Survey scan ($t_{etch} = 600$ s) indicated 50.77 at.% Al, 44.90 at.% N, 2.97 at.% O, and 1.37 at.% Ar for this sample. These results indicate that the AlN films are slightly Al-rich with Al/N ratios of 1.11 and 1.13 for samples deposited using NH_3 and N_2/H_2 plasma processes, respectively. Elemental compositions of the GaN thin films were also determined using XPS ($t_{etch} = 60$ s), where 42.19 at.% Ga, 55.18 at.% N, 1.51 at.% O, 1.13 at.% Ar, and 42.24 at.% Ga, 54.57 at.% N, 1.65 at.% O, 1.54 at.% Ar were detected for the samples deposited using NH_3 and N_2/H_2 plasma, respectively. Although these results suggest N-rich GaN films, it should be noted that the atomic concentration of N is overestimated due to the significant contribution of Auger Ga peaks, which overlap with the N 1s peak.

Table 1 SE results of AlN and GaN thin films deposited using non-optimized HCPA-ALD parameters.

Sample	t_{avg} (nm)	Uniformity ^a of t ($\pm\%$)	GPC (\AA)	n_{avg} ^b	Uniformity ^a of n ($\pm\%$)
AlN (NH_3 plasma)	81.5	1.23	1.02	1.98	0.04
AlN (N_2/H_2 plasma)	76.7	1.05	0.96	1.99	0.15
GaN (NH_3 plasma)	21.1	1.51	0.26	2.17	0.50
GaN (N_2/H_2 plasma)	18.4	1.31	0.23	2.14	0.17

^a Uniformity ($\pm\%$) is calculated by using the formula: $[(\text{max-min})/(2*\text{avg})]*100$.

^b n_{avg} is the average refractive index at 632 nm.

In terms of O impurity concentrations determined by XPS, it seems that the use of HCP source did not result in any improvement as we already reported < 3 at.% O for AlN films deposited using ICP source.^{21,23} However it should be noted that the determination of impurity concentrations by XPS can be challenging. Butcher et al.⁵⁴ reported that using XPS to examine AlN thin films after etching the surface with a 5 kV argon ion beam results in substantial errors in the quantification of O and C impurities present in this material. In another study,⁵⁵ it was reported that XPS can detect 2-5 at.% O – again after Ar ion etching – for commercial GaN samples which have approximately 0.02% bulk O as confirmed by SIMS. In order to further investigate this, we obtained SIMS depth profiles for AlN and GaN thin films deposited using NH_3 plasma (Fig. 1). SIMS data showed that H, C, and O impurities present in both films. Concentrations of O and C were 6.9×10^{20} and 2.5×10^{20} atoms/cc in the bulk AlN film (depth = 30 nm) (Fig. 1(a)), both of which correspond to < 1 at.%. In literature, similar quantities of O and C impurities were reported for AlN thin films deposited using PA-ALD.²⁹ SIMS depth profile of GaN film is given in Fig. 1(b), where lower plateau (7-10 nm) reveals the real concentration of O in the GaN layer. The higher concentration in the 0-5 nm region is an artifact from ion mixing from the surface O. Concentrations of O and C impurities were determined as 1.4×10^{20} and 1.8×10^{20} atoms/cc in the bulk GaN film (depth = 7 nm), both

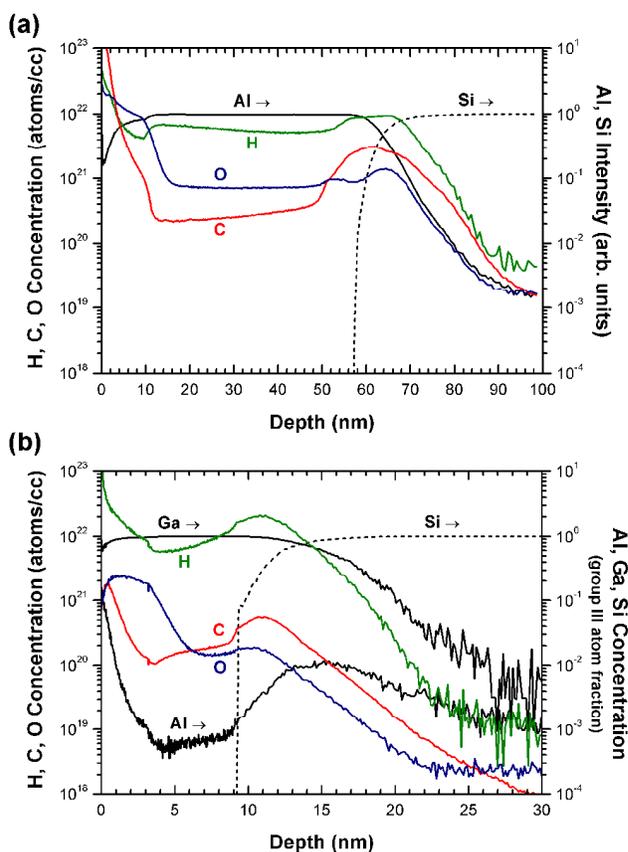


Fig. 1 Impurity concentrations determined by SIMS depth profiling for (a) AlN, and (b) GaN thin films deposited using NH_3 plasma. Silicon is not quantified in the layers, only plotted as the substrate layer marker.

corresponding to < 1 at.%. Concentrations of the H impurities were high in both films with values of 5.6×10^{21} and 8.0×10^{21} atoms/cc for AlN and GaN, respectively. This observation is in parallel with the results recently published by Perros et al.,²⁷ which emphasize the presence of high concentrations (~ 20 at.%) of H impurities in AlN thin films deposited by PA-ALD using NH_3 and N_2/H_2 plasma. Film thicknesses estimated by SIMS were lower than those measured using SE, which is probably due to the different etch rates of AlN and GaN thin films deposited using HCPA-ALD and the standard samples used to quantify impurity concentrations.

GIXRD patterns of AlN and GaN thin films deposited using NH_3 plasma are given in Fig. 2. Same GIXRD patterns were obtained for the AlN and GaN thin films deposited using N_2/H_2 plasma (not shown here); the use of different plasma gases (NH_3 vs. N_2/H_2 plasma) affected neither the peak positions nor the relative intensities of peaks. As revealed by their GIXRD patterns, AlN and GaN films were polycrystalline with (hexagonal) wurtzite crystal structure. Crystallite size values were calculated from the (002) reflections using LPA. Since the size-strain broadening was quite anisotropic we were not able to determine an average value using the Williamson-Hall plot. Crystallite sizes were found to be 19.2 and 24.8 nm for AlN, and 10.2 and 9.3 nm for GaN films deposited using NH_3 and N_2/H_2 plasma processes, respectively. GIXRD pattern of the AlN thin film deposited using quartz-based ICP source is also included in Fig. 2(a) for comparison. The increase in the intensity of (002)

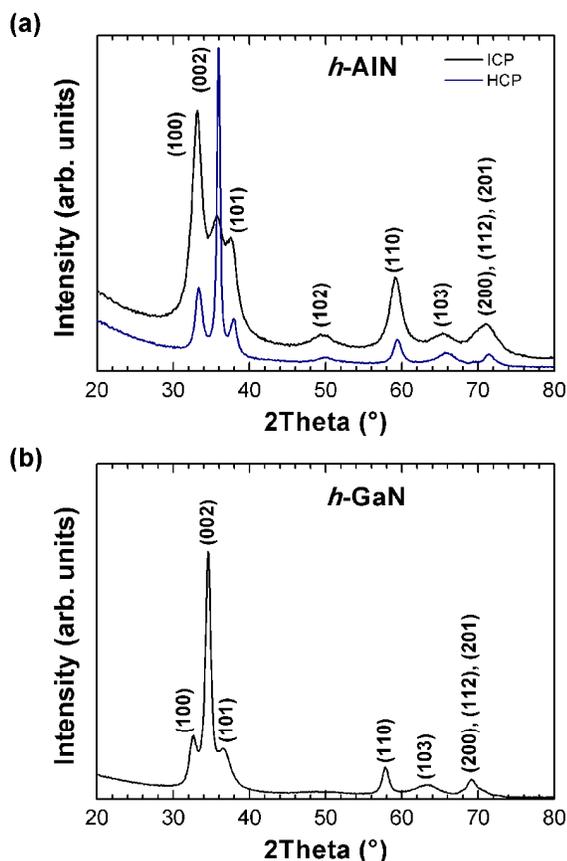


Fig. 2 GIXRD patterns of (a) AlN, and (b) GaN thin films deposited on Si(100) substrates using NH_3 plasma. GIXRD pattern of the AlN thin film deposited using quartz-based ICP source²¹ is also shown in (a) for comparison.

reflection and improvement in the FWHM values suggest larger crystallites and therefore an enhancement in the crystalline quality for films deposited using current configuration with the HCP source. LPA analysis results obtained for the (002) reflections showed that the crystallite sizes, which were 3.4 and 3.1 nm for AlN films deposited using NH_3 and N_2/H_2 plasma, respectively, increased to 20–25 nm with the use of present configuration. Assuming that a significant fraction of O impurities segregate at the grain boundaries, the increase in crystallite size might be indicating a decrease in the O impurity concentration. Fig. 3(a) and (b) are the TEM and high-resolution TEM (HR-TEM) images of the GaN thin film deposited using NH_3 plasma. The ~3-nm-thick amorphous SiO_2 layer at the GaN/Si interface, which is generally named as the “damage layer”, formed during the TEM sample preparation using FIB.⁵⁶ Thickness of the GaN layer was measured from the HR-TEM image (Fig. 3(b)) as 19.2 nm, which is ~2 nm lower than the value measured using SE (i.e. 21.1 nm). XRR, on the other hand, yielded a thickness of 18.2 nm for this sample (sum of the GaN and Ga_2O_3 layer thicknesses in the 4-layer XRR model), which is slightly lower than the value directly measured from HR-TEM image. Besides confirming polycrystallinity of the GaN layer, HR-TEM image also evidences the existence of large crystals in the film, which can extend along the film thickness. Diffraction rings seen in the SAED pattern (Fig. 3(c)) also reveal the polycrystalline nature of GaN thin film, whereas reciprocal lattice

points in this pattern correspond to the diamond lattice of the underlying Si (100) substrate.

Optimization of HCPA-ALD parameters

AlN thin films

HCPA-ALD parameters were optimized at 200 °C for the deposition of AlN thin films using AlMe_3 and N_2/H_2 plasma. For the AlMe_3 saturation curve (Fig. 4(a)) 200 cycles AlN were deposited on Si (100) substrates using different AlMe_3 pulse lengths, where one HCPA-ALD cycle was 0.03–0.12 s AlMe_3 /10 s Ar purge/40 s, 50 + 50 sccm, 300 W N_2/H_2 plasma/10 s Ar purge. As seen in Fig. 4(a), GPC values calculated using SE and XRR data followed the same trend with different values, and GPC slightly decreased with increasing AlMe_3 pulse lengths. Physically, such a decrease is not possible since as the pulse length increases the amount (or number) of AlMe_3 molecules that are being carried to reactor increases, which in turn increases the number of collisions the reactant has with the surface. Precursors may desorb from the surface when long purge times are used, however this should not be the case here since a constant purge time of 10 s was used for all depositions. Therefore the slight decrease in GPC was considered to be within the limits of measurement error, and ignored, and GPC was accepted as constant at ~0.93 Å (as measured by SE) for the AlMe_3 pulse length range of 0.03–0.12 s. Although 0.03 s AlMe_3 seems to be enough for having self-limiting surface reactions, we selected 0.06 s as the optimized value for the following depositions. As the next step of optimization study, flow duration of N_2/H_2 plasma was varied while keeping the other parameters constant (Fig. 4(b)). The data obtained using SE and XRR revealed different trends. According to curve plotted using XRR data, GPC first slightly increases and then reaches saturation for flow durations ≥ 40 s. According to the SE data, it increases from 0.89 to 0.99 Å with longer durations of N_2/H_2 flow within the 20–80 s range. It should be noted that since Si substrates were treated with HF prior to each deposition, the ellipsometric spectra were fitted using a two-layer model (i.e. Cauchy/Si (0.5 mm)) by assuming that the thickness of SiO_2 layer at the AlN/Si interface was negligible. XRR data, on the other hand, were fitted using a four-layer model (i.e. Al_2O_3 /AlN/ SiO_2 /Si); thicknesses of AlN and surface oxide (Al_2O_3) layers were added together for revealing the film thickness, which was then used for the calculation of GPC value. When the thicknesses of native SiO_2 layers were also included to the film thickness values (shown in Fig. 4(b)), the results resembled those obtained by SE, where no saturation behavior was observed. Although the applicability of Cauchy dispersion function for the determination of AlN film thickness was verified by TEM,²¹ results suggest that the increase in GPC values obtained by SE for N_2/H_2 flow durations ≥ 40 s is due to the contribution of native oxide layer. Therefore, it can be presumed that the self-limiting surface reactions are achieved for AlN deposition when 40 s or longer N_2/H_2 plasma is used with predetermined N_2 and H_2 flow rates. Another parameter, which needs to be optimized, is the purge time. If the purge time is not long enough, then the precursor might be introduced into the chamber before the other one is completely purged away. This would result in gas-phase reactions and a significant CVD component in the deposited films. In order to optimize this parameter for the deposition of AlN thin films, we did additional

Cite this: DOI: 10.1039/c0xx00000x

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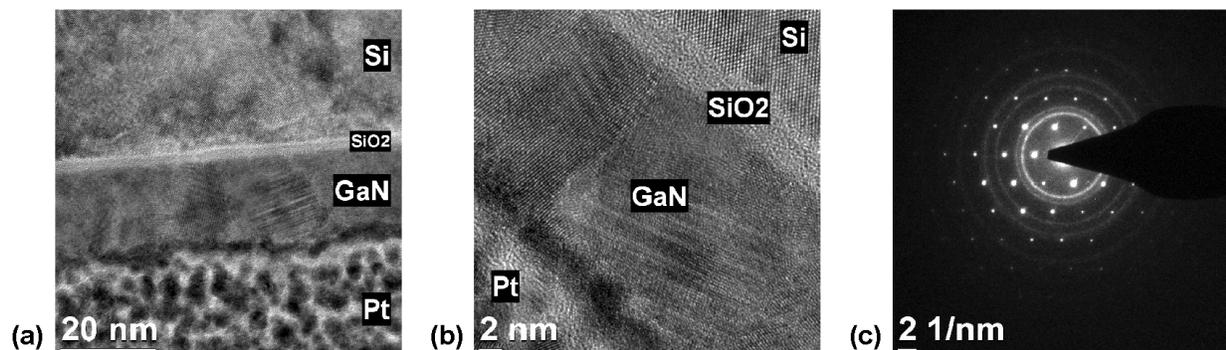


Fig. 3 Cross-sectional (a) TEM, and (b) HR-TEM images of 21-nm-thick GaN thin film deposited on Si (100) substrate using NH_3 plasma. FIB-induced SiO_2 damage layer formed at the GaN/Si interface during TEM sample preparation. (c) SAED pattern of the same sample.

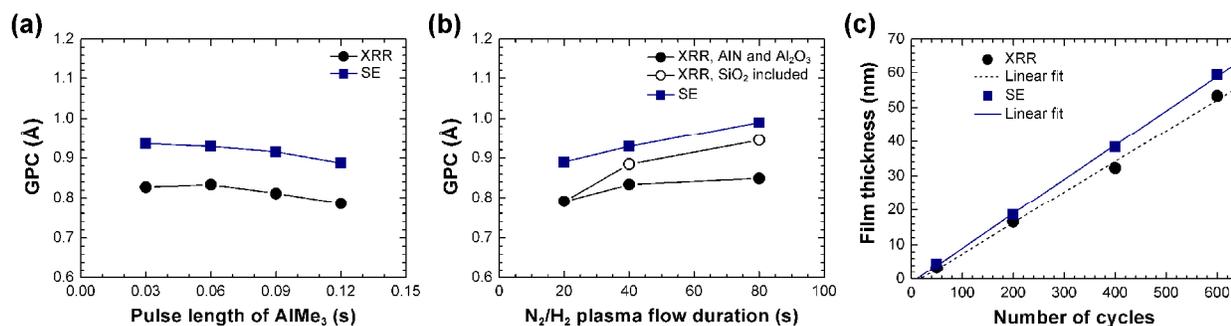


Fig. 4 (a) AlMe_3 , and (b) N_2/H_2 saturation curves at 200 °C. For the AlMe_3 saturation curve, N_2/H_2 flow rate and flow duration were kept constant at 50 + 50 sccm and 40 s, respectively. AlMe_3 pulse length was 0.06 s for the N_2/H_2 saturation curve. (c) AlN film thickness plotted as a function of number of deposition cycles.

depositions using 5 and 20 s purge time, where AlMe_3 pulse length was 0.06 s and N_2/H_2 flow duration was 40 s. The GPC values, which were calculated using SE results, were found to be 0.90, 0.93, and 0.92 Å for 5, 10, and 20 s of purging, respectively. This confirms that 10 s purging is long enough to avoid any gas-phase reactions, and even 5 s can be used to have shorter cycles. The optimized recipe was therefore determined for the AlN growth as 0.06 s AlMe_3 /10 s Ar purge/40 s, 50 + 50 sccm, 300 W N_2/H_2 plasma/10 s Ar purge. In Fig. 4(c), AlN film thicknesses measured using SE and XRR were plotted as a function of number of cycles. Results indicated linear growth with a slight nucleation delay. Slope of the linear fit of SE data revealed the GPC at 200 °C as ~ 1.0 Å.

GaN thin films

HCPA-ALD parameters were optimized at 200 °C for the deposition of GaN thin films using GaMe_3 and N_2/H_2 plasma, where 300 cycles were deposited using 0.015-0.09 s GaMe_3 /5-20 s Ar purge/20-80 s, 50 + 50 s, 300 W N_2/H_2 plasma/5-20 s Ar purge. Fig. 5(a) shows the GaMe_3 saturation curve, which was obtained by varying the GaMe_3 pulse length between 0.015 and 0.09 s, while keeping the purge time and N_2/H_2 plasma flow duration constant at 10 and 40 s, respectively. SE and XRR data

revealed curves with similar shapes but slightly different values. When GaMe_3 pulse length was increased from 0.015 to 0.03 s, GPC (determined by SE) negligibly increased from 0.30 to 0.31 Å; for 0.06 and 0.09 s it was 0.32 Å. Therefore, GPC was constant within the range of 0.015-0.09 s, which evidences the self-limiting growth of GaN. In the following step, N_2/H_2 plasma duration was varied between 20 and 80 s (Fig. 5(b)). GaMe_3 pulse length and purge time were 0.03 and 10 s, respectively. According to both SE and XRR data, GPC increased upon increasing the N_2/H_2 flow duration from 20 to 40 s, but then saturated and did not change when flow duration was further increased to 80 s, which again clearly indicates the existence of “self-limiting” growth mechanism. Therefore, optimized values of GaMe_3 pulse length and N_2/H_2 flow duration were determined as 0.03 and 40 s, respectively. The effect of purge time was studied by performing depositions with 5, 10, and 20 s of purge time, all of which resulted with the same GPC. Therefore the optimized recipe for GaN deposition was determined as 0.03 s GaMe_3 /10 s Ar purge/40 s, 50 + 50 sccm, 300 W N_2/H_2 plasma/10 s Ar purge. Fig. 5(c) shows GPC values for the optimized recipe, which were plotted as a function of number of cycles. Both SE and XRR data show a similar trend, where GPC

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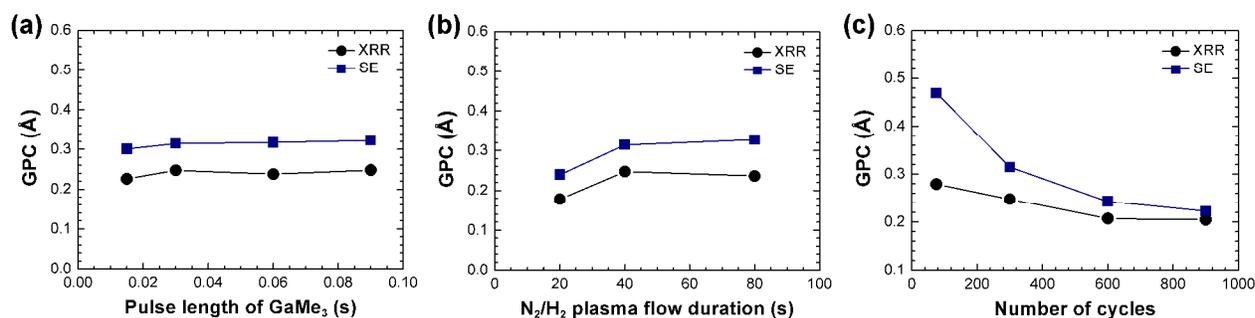


Fig. 5 (a) GaMe₃, and (b) N₂/H₂ saturation curves at 200 °C. For the GaMe₃ saturation curve, N₂/H₂ flow rate and flow duration were kept constant at 50 + 50 sccm and 40 s, respectively. GaMe₃ pulse length was 0.03 s for the N₂/H₂ saturation curve. (c) GPC plotted as a function of number of deposition cycles. Data suggests substrate-enhanced growth of GaN thin films.

5 decreases with increasing number of deposition cycles. This suggests substrate-enhanced growth, where GPC of GaN on Si is higher when compared to that of GaN on itself. This kind of a growth behavior can occur if the number of reactive sites on the substrate is higher than on the ALD-grown material.⁶

10 AIN and GaN thin films deposited using optimized HCPA-ALD parameters

600 cycles AIN and 900 cycles GaN were deposited at 200 °C using optimized HCPA-ALD parameters. Table 2 summarizes the SE results of these thin film samples together with the results of 15 AIN and GaN films deposited using N₂/H₂ plasma with non-optimized parameters. Note that the non-optimized parameters used for the deposition of AIN and GaN thin films using N₂/H₂ plasma were identical to optimized parameters except the pulse lengths of AlMe₃ and GaMe₃. Furthermore, it has been shown in 20 the previous section that the metalorganic pulse lengths used in the non-optimized recipes (0.1 s for AlMe₃ and 0.015 s GaMe₃) also result in self-limiting growth mechanism (see Fig. 4(a) and 5(a)). For both AIN and GaN thin films, the use of optimized HCPA-ALD parameters resulted in a better thickness uniformity 25 over 4" Si substrate. Refractive indices of AIN (0.06 s AlMe₃) and GaN (0.015 s GaMe₃) thin films were found as 1.94 and 2.14 at 632 nm, respectively. These values increased to 1.99 and 2.17 when higher metalorganic pulse lengths were employed, which might be due the deposition of denser films. Refractive index 30 values of AIN and GaN films determined by the Cauchy dispersion function are both in good agreement with those reported in the literature.^{52,53}

The change in metalorganic pulse lengths did not affect the chemical compositions of films. Chemical bonding states at the 35 film surface ($t_{etch} = 0$ s) and in the bulk film ($t_{etch} = 300$ and 60 s for AIN and GaN, respectively) were determined for the samples deposited using optimized parameters by the evaluation of their HR-XPS scans (Fig. 6 and 7). Al 2p HR-XPS scan obtained from the AIN film surface (Fig. 6(a)), was fitted by two subpeaks 40 (subpeaks A and B) located at 73.78 and 72.92 eV, corresponding to Al-O⁵⁷ and Al-N^{57,58} bonds, respectively. Upon Ar ion etching,

Table 2 SE results of AIN and GaN thin films deposited using N₂/H₂ plasma.

Sample	t_{avg} (nm)	Uniformity ^b of t (±%)	GPC (Å)	n_{avg} ^c	Uniformity ^b of n (±%)
AIN (0.06 s AlMe ₃) ^a	59.2	0.57	0.99	1.94	0.28
AIN (0.1 s AlMe ₃)	76.7	1.05	0.96	1.99	0.15
GaN (0.015 s GaMe ₃)	18.4	1.31	0.23	2.14	0.17
GaN (0.03 s GaMe ₃) ^a	20.1	0.77	0.22	2.17	0.32

^a Optimized values for the HCPA-ALD of AIN and GaN thin films.

^b Uniformity (±%) is calculated by using the formula: [(max-min)/(2*avg)]*100.

^c n_{avg} is the average refractive index at 632 nm.

subpeak A (corresponding to the Al-O bond) disappeared, and therefore Al 2p HR-XPS scan was fitted with a single peak 50 (subpeak B, 72.71 eV), which was attributed to the Al-N bonding state. Additional information about the chemical bonding states in the AIN film was provided by the N 1s spectrum (Fig. 6(b)). N 1s scan obtained from the AIN film surface, was fitted using three subpeaks located at 398.42 (subpeak A), 397.27 (subpeak B), and 55 396.20 eV (subpeak C), corresponding to N-Al-O (surface only),⁵⁸ N-Al-O,⁵⁸ and N-Al^{58,59} bonds, respectively. N 1s HR-XPS scan obtained after Ar ion etching revealed the existence of N-Al-O (subpeak B, 397.37 eV) and N-Al (subpeak C, 395.79 eV) bonds in the bulk film. Subpeaks corresponding to Al-N and 60 N-Al bonds in the Al 2p and N 1s spectra, respectively, confirmed the presence of AIN, whereas the oxynitride peak (N-Al-O) was related to the < 3 at.% O in bulk film detected by the XPS survey scan.

Ga 3d and N 1s HR-XPS spectra of the GaN thin film sample 65 are given in Fig. 7(a) and 7(b), respectively. Ga3d and N1s spectra measured from a commercial MOCVD-grown GaN sample were also included in these figures for comparison. Ga 3d scan revealed the existence of Ga-O^{60,61} and Ga-N⁶⁰⁻⁶² bonds at the film surface with subpeaks A (20.27 eV) and B (19.46 eV), 70 respectively. The subpeak D located at 16.98 eV was related to the contribution from N 2s core level.^{61,63} N 1s spectrum obtained from the film surface was fitted using three subpeaks located at 396.87 (subpeak A), 395.37 (subpeak B), and 394.36 eV

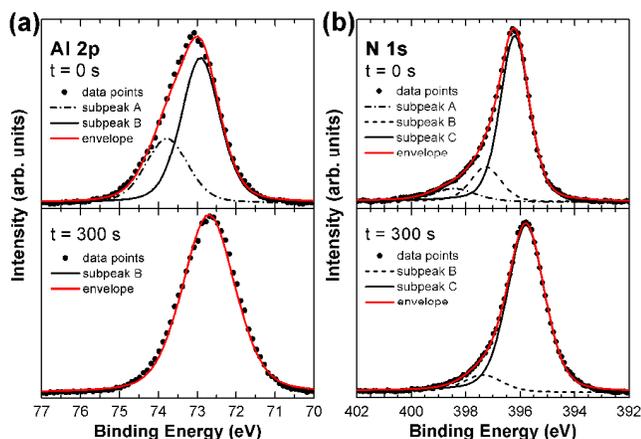


Fig. 6 (a) Al 2p, and (b) N 1s HR-XPS scans of 59.2-nm-thick AlN thin film deposited on Si (100) substrate using optimized HCPA-ALD parameters.

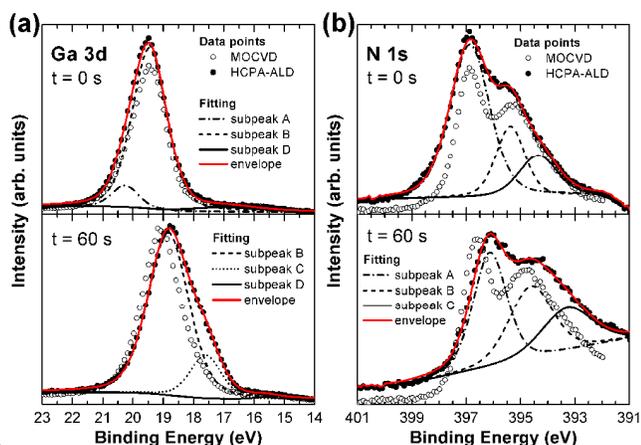


Fig. 7 (a) Ga 3d, and (b) N 1s HR-XPS scans of 20.1-nm-thick GaN thin film deposited on Si (100) substrate using optimized HCPA-ALD parameters.

(subpeak C). Subpeak A was assigned as the N-Ga bond,⁶⁴ whereas subpeaks B and C were identified as the Auger Ga peaks.⁶⁵ Ga 3d and N 1s spectra measured from the surface of GaN thin film deposited by HCPA-ALD were in good agreement with those measured from the surface of commercial MOCVD-grown sample. Ga 3d HR-XPS spectrum of the etched film was fitted with three subpeaks located at 18.83 (subpeak B), 17.60 (subpeak C), and 15.61 eV (subpeak D), corresponding to Ga-N and Ga-Ga⁶² bonding states, and contribution from the N 2s core level, respectively. It is believed that the Ga-Ga bond is not associated with the sample, but forms during Ar ion etching due to the accumulation of metallic Ga on the surface of GaN thin film sample.^{55,66} N 1s spectrum obtained from the etched film was fitted using three subpeaks, which were again assigned as the N-Ga bond (subpeak A, 396.23 eV) and Auger Ga peaks (subpeak B, 394.72 eV and subpeak C, 393.39 eV). The spectral locations of the subpeaks corresponding to a particular bonding state, contribution, or Auger peak shifted to lower binding energies for etched GaN samples. The spectral locations of Ga 3d and N 1s peaks ($t_{etch} = 60$ s) were also found to be slightly different for HCPA-ALD- and MOCVD-grown GaN samples. This might be related to the reference that we used for the correction of charging effects. For etched samples it is generally

convenient to use the spectral position of Ar 2p peak for determining the amount of shift needed. However, in our case, Ar 2p peaks were quite weak to be used for correction. Therefore we shifted the HR-XPS spectra of etched samples – as we were shifting the spectra obtained from film surface – by an amount determined by the location of adventitious C peak (C 1s). This approach might not work, as in the present case, if charging of the film surface and etched region are different due to their distinct chemical compositions.

GIXRD patterns of the AlN and GaN thin films deposited on Si (100) and Si (111) substrates using optimized HCPA-ALD parameters (shown in part in Fig. 10 and Fig. 11) were identical to those given in Fig. 2(a) and (b), respectively, in terms of peak positions and relative intensities of the peaks. As their GIXRD indicated, AlN and GaN thin films deposited at 200 °C were single-phase and polycrystalline with hexagonal wurtzite crystal structure. The GIXRD pattern of the 59.2-nm-thick AlN thin film deposited on *c*-plane sapphire substrate was slightly different than those obtained from samples deposited on Si (100) and Si (111) substrates. The same seven reflections of the *h*-AlN phase appeared at the exact same 2Theta positions, however the intensity of (100) reflection was almost as high as that of (002) reflection. Intensity of the (103) reflection was also slightly higher for the sample deposited on *c*-plane sapphire. In the case of GaN, the difference between GIXRD patterns of thin films deposited on Si and *c*-plane sapphire substrates was remarkable. Fig. 8 is the GIXRD pattern of a 20.1-nm-thick GaN thin film deposited on *c*-plane sapphire. (101), (110) reflections and the 60 peak encloses (200), (112), (201) reflections disappeared for this sample. The intensities of (100) and (002) reflections decreased, and the intensity of (103) reflection increased significantly. It should be noted that the GIXRD method, because of its geometry, is insensitive to the planes that are parallel to the substrate, therefore disappearance of the peaks might be an indication of preferred orientation.

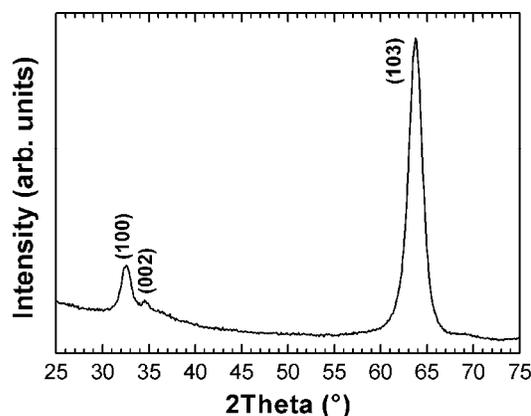


Fig. 8 GIXRD pattern of 20.1-nm-thick GaN thin film deposited on *c*-plane sapphire substrate using optimized HCPA-ALD parameters.

XRR results of AlN and GaN thin films deposited on Si (100) substrates using N₂/H₂ plasma with optimized HCPA-ALD parameters are given in Table 3. Film thicknesses estimated by XRR were lower than those measured using SE. As shown previously, the actual film thickness lies between the values measured by SE and XRR. The mass densities (ρ) of AlN and GaN thin films were estimated as 2.82 and 5.86 g/cm³, which are

lower than the recognized values of 3.23 and 6.15 g/cm³, respectively.⁶⁷ The estimated mass density of AlN thin film (2.82 g/cm³) was higher than those reported in literature for AlN films deposited by PA-ALD at 200 °C ($\rho = 2.34\text{--}2.65$ g/cm³).^{24,27} XRR also revealed the rms roughnesses of these AlN and GaN thin films as 2.16 and 1.54 nm, which are higher than the values directly measured using AFM. Fig. 9 shows the 2D surface morphologies of AlN and GaN thin films deposited on Si (100) substrates. Rms roughnesses of the AlN and GaN thin films were measured from a 1 $\mu\text{m} \times 1 \mu\text{m}$ scan area as 1.97 and 0.64 nm, respectively. Rms surface roughnesses were 1.96 and 0.51 nm for AlN and GaN thin films deposited on Si (111) substrates, and 1.62 and 0.26 nm for AlN and GaN thin films deposited on *c*-plane sapphire substrates.

Table 3 XRR results of AlN and GaN thin films deposited using optimized HCPA-ALD parameters.

Sample	$t_{\text{Nit.}}^a$ (nm)	$t_{\text{Ox.}}^b$ (nm)	ρ (g/cm ³)	r_{rms} (nm)
AlN	53.21	0.09	2.82	2.16
GaN	17.00	1.40	5.86	1.54

^a $t_{\text{Nit.}}$ is the thickness of nitride layer; i.e. AlN or GaN.

^b $t_{\text{Ox.}}$ is the thickness of surface oxide layer; i.e. Al₂O₃ or Ga₂O₃.

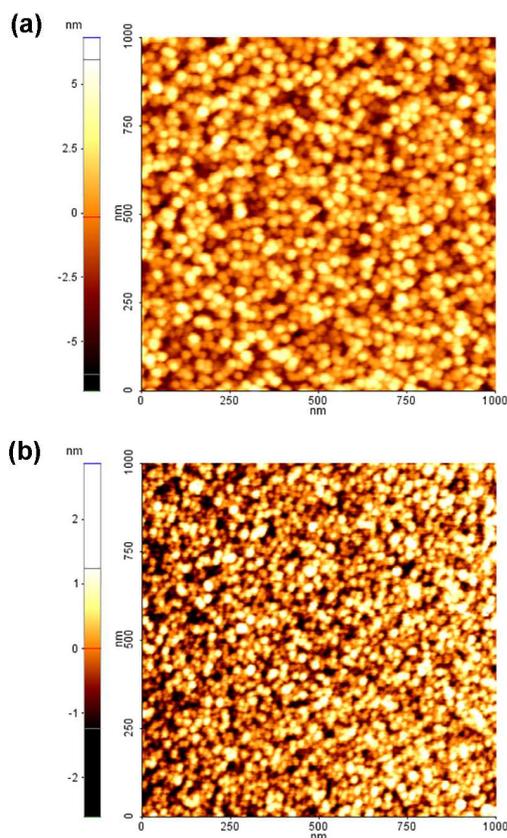


Fig. 9 Surface morphologies of (a) 59.2-nm-thick AlN, and (b) 20.1-nm-thick GaN thin films deposited on Si (100) substrates using optimized HCPA-ALD parameters.

AlN and GaN thin films deposited using N₂ plasma

The effect of plasma gas composition on the properties of deposited nitride thin films was studied. For this purpose, AlN and GaN films were deposited on Si (100) substrates using N₂

plasma, as well as N₂/H₂ plasma with decreased H₂ flow (i.e. 25 sccm). SE results of these thin film samples are summarized in Table 4, where the thicknesses and refractive indices of the thin films deposited using N₂/H₂ plasma (50 + 25 sccm) were comparable to those of the films deposited using optimized parameters. Thicknesses of the AlN and GaN thin films increased tremendously when N₂ was used as the plasma gas. Furthermore, refractive index values decreased upon the use of N₂ plasma, which indicates deterioration of film quality. GIXRD patterns of the AlN and GaN thin films deposited with N₂/H₂ and N₂ plasma are given in Fig. 10(a) and (b), respectively, together with the GIXRD patterns of films deposited using optimized HCPA-ALD parameters. As seen from these figures, decreasing H₂ flow rate from 50 to 25 sccm did not affect the crystalline qualities of AlN and GaN thin films, the same GIXRD patterns were obtained in both cases. The use of N₂ plasma without any H₂, on the other hand, resulted in amorphous GaN thin films. In the case of AlN, the crystallinity is almost lost as the reflections of the hexagonal wurtzite phase became barely visible. We observed similar results for the AlN and GaN films deposited using previous configuration with quartz-based ICP source,⁴⁹ where the use of N₂ plasma resulted in high concentrations of C and O impurities in the deposited films and destroyed crystallinity. The presence of C impurities (8.0 and 9.1 at.% for AlN and GaN, respectively)⁴⁹ suggest that the organic ligands are trapped inside the growing film since N₂ plasma without any H₂ is not efficient in terms of removing the ligands of the chemisorbed trimethylmetal precursors. This might be avoided at higher temperatures, where the methyl ligands of the precursor molecules get free by self-decomposition. Although it has been thought that the high O concentrations in the films (48.5 and 4.5 at.% for AlN and GaN, respectively)⁴⁹ are related to plasma-related oxygen contamination, recently Perros et al.²⁷ showed that the N₂ plasma process results in unstable AlN films, which oxidizes upon exposure to atmosphere. It is also worth mentioning that there were particles on the surfaces of AlN and GaN films deposited using N₂ plasma. The particles were larger in the case of GaN thin film, which also showed color variations that indicate thickness non-uniformity. The formation of these particles cannot be attributed to gas-phase reactions since we already showed that 10 s purging is sufficient to avoid overlapping of the trimethylmetal precursor and plasma gas (50 sccm N₂ together with 50 sccm H₂). Therefore, the only explanation would be the formation of solid byproducts as a result of the reaction between trimethylmetal compounds and N radicals. These results show that the N₂ plasma process is not eligible for the low-temperature deposition of AlN and GaN thin films.

Table 4 SE results of AlN and GaN thin films deposited using N₂/H₂^a and N₂ plasma.

Reactant	t_{AlN} (nm)	n_{AlN}	t_{GaN} (nm)	n_{GaN}
N ₂ /H ₂ plasma ^a	57.2	1.94	20.6	2.18
N ₂ plasma	83.6	1.59	111.1	1.88

^a Flow rates of N₂ and H₂ were 50 and 25 sccm, respectively.

Al_xGa_{1-x}N thin films deposited by digital alloying

Al_xGa_{1-x}N thin films with different compositions were deposited at 200 °C on Si (100), Si (111), and *c*-plane sapphire substrates. In order to adjust the alloy composition, different numbers of

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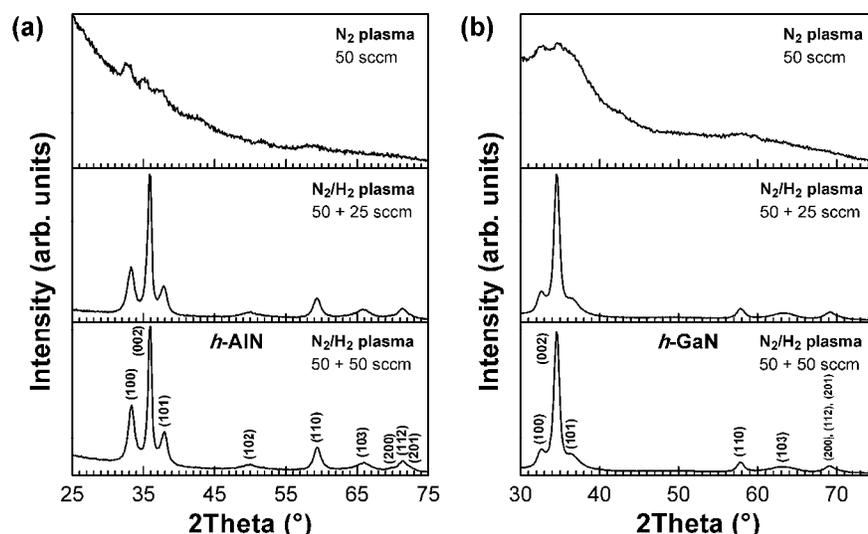


Fig. 10 GIXRD patterns of (a) AlN, and (b) GaN thin films deposited on Si (100) substrates using N₂/H₂ (50 + 50 sccm), N₂/H₂ (50 + 25 sccm), and N₂ (50 sccm) plasma.

AlN and GaN subcycles were used in the main cycle; i.e. AlN:GaN = 1:3, 1:1, and 3:1. 800 subcycles were deposited in each case, where AlN subcycles were deposited using the optimized HCPA-ALD parameters, whereas GaN subcycles were deposited using the optimized recipe with 0.015 s GaMe₃ pulse length. GIXRD patterns of the Al_xGa_{1-x}N thin films are given in Fig. 11, together with those of AlN and GaN thin films deposited using optimized process parameters. As seen from these patterns, as the number of AlN subcycles increase, the peaks shift towards higher 2Theta values due to the incorporation of Al into the wurtzite lattice. Using these data, the alloy composition, *x*, can be determined for each Al_xGa_{1-x}N thin film using the Vegard's rule, which simply states that the lattice parameters of an alloy will vary linearly between the end members.⁶⁸ It should be noted that this rule applies to unstrained materials, where composition is the only factor affecting the lattice parameters. For the *c* lattice parameter of Al_xGa_{1-x}N, Vegard's rule is given as:

$$c_{Al_xGa_{1-x}N} = x c_{AlN} + (1 - x) c_{GaN} \quad (1)$$

The interplanar spacing values calculated from peak positions using the well-known Bragg's law are annotated on Fig. 11 for (002) and (110) planes. Lattice parameters *a* and *c* were roughly calculated by substituting these *d*₁₁₀ and *d*₀₀₂ values, respectively, to below formula (Eq. 2), which relates the interplanar spacing (*d*_{*hkl*}), miller indices (*hkl*) and lattice parameters (*a* and *c*) for hexagonal crystals. Alloy compositions, *x*, were then calculated from *c* lattice parameters using the Vegard's rule (Eq. 1).

$$\frac{1}{d^2} = \frac{4}{3} \left(\frac{h^2 + hk + k^2}{a^2} \right) + \frac{l^2}{c^2} \quad (2)$$

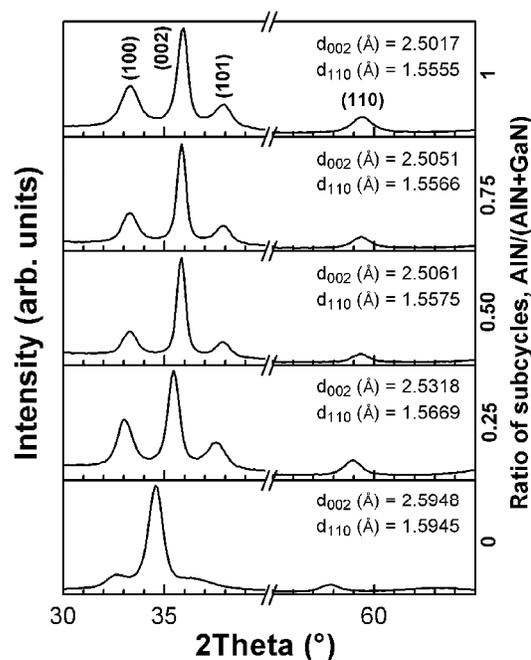


Fig. 11 GIXRD patterns of AlN, GaN, and Al_xGa_{1-x}N thin films deposited on Si (100) substrates.

Theoretical values of alloy composition (*x*_{Theo.}) were also determined using the formula,

$$x_{Theo.} = \frac{n_{s,AlN} GPC_{AlN}}{n_{s,AlN} GPC_{AlN} + n_{s,GaN} GPC_{GaN}} \quad (3)$$

where *n*_{s,AlN} is the number of AlN subcycles, *n*_{s,GaN} is the number

of GaN subcycles, and GPC_{AlN} and GPC_{GaN} are the deposition rates of AlN and GaN (0.015 s GaMe₃) thin films, which were reported as 0.99 and 0.23 Å/cycle, respectively, in the previous sections. The calculated lattice parameters, c/a ratios, and alloy compositions are summarized in Table 5.

Table 5 Lattice parameters, c/a ratios, and alloy compositions of AlN, GaN, and Al_xGa_{1-x}N thin films.

RS ^a	c^b (Å)	a^c (Å)	c/a	$x_{Veg.}^d$	$x_{Theo.}^e$
0 (GaN)	5.1896	3.1889	1.627	0	0
0.25	5.0636	3.1338	1.616	0.68	0.59
0.50	5.0122	3.1151	1.609	0.95	0.81
0.75	5.0101	3.1133	1.609	0.96	0.93
1 (AlN)	5.0034	3.1110	1.608	1	1

^a RS is the ratio of subcycles; i.e. $n_s AlN / (n_s AlN + n_s GaN)$.

^b Calculated using the position of (002) reflection.

^c Calculated using the position of (110) reflection.

^d $x_{Veg.}$ is the alloy composition calculated from c values using Vegard's rule (Eq. 1).

^e $x_{Theo.}$ is the alloy composition calculated theoretically using GPC values (Eq. 3).

Although the calculated a lattice parameters of AlN and GaN are in good agreement with those reported in literature for their nominally strain-free counterparts, c lattice parameters were found to be higher (0.45% for AlN and 0.06% for GaN with respect to the highest c value reported in literature) than those of strain-free AlN and GaN thin films.⁶⁸ These results indicate the presence of strain, which limit the applicability of Vegard's rule to Al_xGa_{1-x}N thin films deposited by HCPA-ALD. In order to minimize errors, alloy compositions were calculated by substituting c lattice parameters of HCPA-ALD-grown AlN and GaN films into Eq. 1. Theoretical values calculated using Eq. 3, were lower than those found by the Vegard's rule. However, it should be noted that the theoretical calculation of alloy composition is not straightforward in the present case since the deposition rate of AlN on GaN and/or the deposition rate of GaN on AlN might be different than those of AlN on AlN and GaN on GaN, respectively. Moreover, the HCPA-ALD of AlN exhibits a slight nucleation delay, and the GPC of GaN is higher in the beginning of growth (see Fig. 4(c) and 5(c)).

Thicknesses of the Al_{0.68}Ga_{0.32}N, Al_{0.95}Ga_{0.05}N and Al_{0.96}Ga_{0.04}N films were determined as 25.4, 42.4, and 57.9 nm, respectively, using SE. These values were found to be lower than those calculated theoretically due to uncertainties in GPC values as discussed in the above paragraph. Cross-sectional bright-field scanning TEM (STEM) and HR-TEM images of Al_{0.68}Ga_{0.32}N thin film are shown in Fig. 12(a) and (b), respectively. From Fig. 12(a), it is seen that the Al_{0.68}Ga_{0.32}N layer is highly uniform. Thickness of the Al_{0.68}Ga_{0.32}N thin film was measured directly from Fig. 12(b) as 26.3 nm, which agrees well with the result obtained from SE. HR-TEM image (Fig. 12(b)) and SAED pattern (not shown here) revealed the polycrystalline nature of this sample, which has also been indicated in Fig. 11 for the film deposited on Si (100) substrate.

In the previous sections, we reported the refractive index values of AlN (0.06 s AlMe₃) and GaN (0.015 s GaMe₃) as 1.94 and 2.14 at 632 nm, respectively. Refractive index values decreased from 2.03 to 1.96 as the Al content of Al_xGa_{1-x}N increased from 0.68 to 0.96 (Fig. 13(a)). Refractive indices of the Al_xGa_{1-x}N thin films were found to be quite close to that of AlN

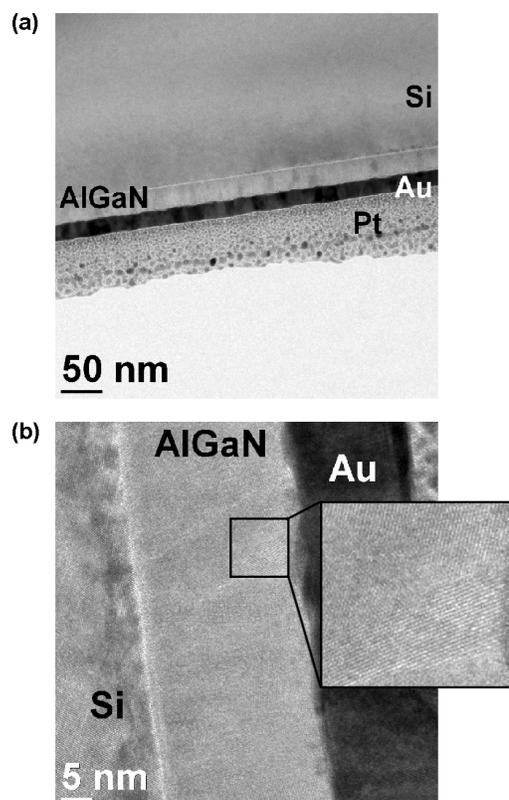


Fig. 12 Cross-sectional (a) bright-field STEM, and (b) HR-TEM images of 25.4-nm-thick Al_{0.68}Ga_{0.32}N thin film deposited on Si (111) substrate using N₂/H₂ plasma.

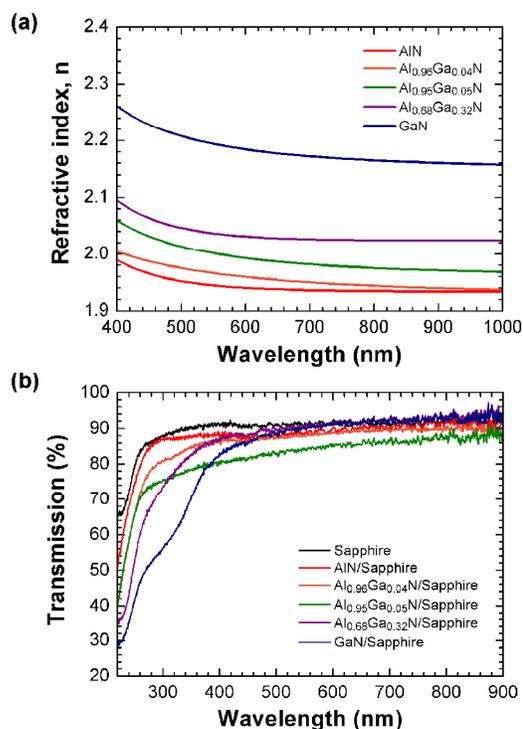


Fig. 13 (a) Spectral refractive indices, and (b) optical transmission spectra of AlN, GaN, and Al_xGa_{1-x}N thin films deposited on Si (100) and double side polished c -plane sapphire substrates, respectively.

($n = 1.94$) since the ternary alloys deposited in this study were all Al-rich. Optical transmission spectra of AlN, GaN, and $\text{Al}_x\text{Ga}_{1-x}\text{N}$ thin films deposited on double side polished sapphire substrates at 200 °C are given in Fig. 13(b). The optical transmission spectrum of sapphire is also included in the figure. Film transmissions were found to be equal to the substrate transmission (~93%) in the visible spectrum, indicating absorption-free films. A significant decrease in the UV transmission was observed at wavelengths < 260 nm, which is caused by the main band gap absorption. In addition, optical band edge values of the films shifted to lower wavelengths with increasing Al content. The transmission data obtained from a 20.1-nm-thick GaN film exhibited a weak shoulder at lower wavelength values. The widening of the absorption edge particularly observed for this thin film sample might be attributed to strain-induced defects⁶⁹ and/or quantum confinement effect⁷⁰ due to the small crystallite size, which was estimated as 9.3 nm by the LPA analysis.

Summary and Conclusions

In this paper we have demonstrated the HCPA-ALD of crystalline AlN, GaN and $\text{Al}_x\text{Ga}_{1-x}\text{N}$ thin films at low temperature (i.e. 200 °C) using trimethylmetal precursors and NH_3 or N_2/H_2 plasma. Preliminary depositions carried out using non-optimized process parameters resulted with reasonably uniform AlN and GaN films with wafer-level non-uniformities less than $\pm 1.5\%$. XPS survey scans detected 2.5-3.0 and 1.5-1.7 at.% O in these AlN and GaN thin films, respectively, after they were etched *in situ* with a beam of Ar ions under UHV conditions. C was detected only at the film surfaces and there were no C impurities in the bulk films as determined by XPS. Since the Ar ion etching may lead to substantial errors in the quantification of O and C impurities present in AlN and GaN thin films, complimentary SIMS analyses were performed on the films deposited using NH_3 plasma, which revealed the presence of O, C (both < 1 at.%) and H impurities in the films. GIXRD patterns exhibited polycrystalline AlN and GaN thin films with (hexagonal) wurtzite crystal structure. Crystallite sizes were 19.2 and 24.8 nm for AlN, and 10.2 and 9.3 nm for GaN films deposited using NH_3 and N_2/H_2 plasma, respectively. HR-TEM image of the GaN thin film deposited using NH_3 plasma further revealed the existence of relatively large crystals in the film, which can extend along the film thickness.

HCPA-ALD parameters were optimized at 200 °C for the deposition of AlN and GaN thin films. Trimethylmetal precursor and N_2/H_2 saturation curves evidenced the self-limiting growth of AlN and GaN at this temperature. AlN exhibited linear growth with a slight nucleation delay. GPC of AlN was high; i.e. ~ 1.0 Å. In the case of GaN, GPC decreased with the increasing number of deposition cycles, which indicates substrate-enhanced growth. GPC was found as 0.22 Å for the 900-cycle GaN deposition. 59.2-nm-thick AlN and 20.1-nm-thick GaN thin films deposited using optimized process parameters were characterized using SE, HR-XPS, GIXRD, XRR, and AFM. Refractive indices of AlN and GaN thin films were determined as 1.94 and 2.17 at 632 nm, respectively, using the Cauchy dispersion function. Al 2p (Ga 3d) and N 1s HR-XPS spectra confirmed the metal nitride bonding states in AlN (GaN) films. The mass densities of AlN and GaN

thin films were estimated as 2.82 and 5.86 g/cm³ using XRR. Rms roughness values determined by XRR were higher than those directly measured using AFM; i.e. 1.97 and 0.64 nm for AlN and GaN thin films deposited on Si (100) substrates, respectively. Results of the depositions carried out using N_2 plasma have shown that this process results in low-quality films, and therefore is not eligible for the low-temperature deposition of AlN and GaN.

$\text{Al}_x\text{Ga}_{1-x}\text{N}$ thin films were obtained via digital alloying, where the main HCPA-ALD cycle consisted of different number of AlN and GaN subcycles; i.e. AlN:GaN = 1:3, 1:1, and 3:1. Alloy compositions were determined by the Vegard's rule as 0.68 (AlN:GaN = 1:3), 0.95 (1:1), and 0.96 (3:1) using the *c* lattice parameters, which were roughly calculated from the (002) peak positions. The *c* lattice parameters of binary AlN and GaN thin films were also estimated and used for the calculations in order to minimize the errors that may arise due to the presence of strain in deposited films. Refractive index values of the $\text{Al}_x\text{Ga}_{1-x}\text{N}$ thin films decreased from 2.03 to 1.96 as the Al content increased from 0.68 to 0.96. Transmissions of AlN, GaN, and $\text{Al}_x\text{Ga}_{1-x}\text{N}$ thin films were equal to the substrate transmission (~93%) in the visible spectrum, indicating absorption-free films. Optical band edge values of the $\text{Al}_x\text{Ga}_{1-x}\text{N}$ films shifted to lower wavelengths with increasing Al content, which confirms the adjustability of band edge values with compositional digital alloying.

Acknowledgments

This work was performed at UNAM – Institute of Materials Science and Nanotechnology, which is supported by the State Planning Organization of Turkey through the National Nanotechnology Research Center Project. Authors acknowledge Dr. S. Butcher (Meaglow Ltd.) for the helpful discussions and comments. C. O.-A. acknowledges TUBITAK-BIDEB for National PhD Fellowship. N. B. acknowledges support from Marie Curie International Reintegration Grant (NEMSmart, Grant # PIRG05-GA-2009-249196). A. K. O. and N. B. acknowledge the financial support from TUBITAK (Project # 112M004 and 112M482). M. Guler from UNAM is acknowledged for TEM sample preparation and HR-TEM imaging.

Notes and references

^a UNAM – National Nanotechnology Research Center, Bilkent University, Ankara, 06800, Turkey. Fax: +90 (312) 266 4365; Tel: +90 (312) 290 3556; E-mail: ozgit@bilkent.edu.tr, biyikli@unam.bilkent.edu.tr

^b Institute of Materials Science and Nanotechnology, Bilkent University, Ankara, 06800, Turkey.

^c Department of Electrical and Electronics Engineering, Bilkent University, Ankara, 06800, Turkey.

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